

<b>Notice of References Cited</b>	Application/Control No. 10/722,776		Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner NANCY BITAR		Art Unit 2624	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0278324	12-2005	Fan et al.	707/006
*	B	US-7,065,230	06-2006	Yuasa et al.	382/104
*	C	US-7,191,175	03-2007	Evans, Lynne Marie	707/5
*	D	US-7,139,764	11-2006	Lee, Shih-Jong J.	707/100
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Automatic Subspace Clustering of High Dimensional Data for Data Mining Application, Agrawal et al.			
	V	Brin et al (Near Neighbor Search in Large Metric Spaces, Nov 20, 1995).			
	W	OP-Cluster: Clustering by Tendency in High Dimensional Space, Jinze Liu and Wei Wan			
	X	I.			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.